

Is Your Testing N-wise or Unwise?

Pairwise and N-wise Patterns in SystemVerilog for Efficient Test Configuration and Stimulus

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Agenda

Introduction to pairwise/N-wise test generation
Using our SystemVerilog N-wise implementation
Performance concerns, additional features
Application suggestions
Wrap-up

Introduction to Pairwise and N-wise

- Testing can never be exhaustive
 - too much state, too many combinations
- Software testing has used *pairwise* for many years
 - an attempt to focus our finite testing effort as effectively as possible
 - complements constrained-random – does not replace it!
- Basic principle: don't try to test all possible combinations of all parameters, but instead

for every *pair* of parameters,
test every combination of that pair

- Picks up any bug that is caused when two parameters have specific values
 - usually, with less testing effort than constrained-random

Configurations Must Be Tested

- 8-bit configuration register for a simple DUT:



- F3 has only 3 legal values
 - **192** values to be tested!
- Each configuration should be tested thoroughly
 - ideally, full coverage on each
 - Not enough project time!
 - In practice, only a few important (lead customer?) configurations will be tested fully

Major concern for IP authors/vendors

Why Pairwise?

- Testing every parameter value is easy but not so useful
 - only 4 tests cover every value of each parameter in isolation

F1	F2	F3	F4	F5
00	00	00	0	0
01	01	01	1	1
10	10	10	0	0
11	11	00	1	1

Observation:

Bugs are often triggered by interaction of *two* values

- Test **every** combination of **pairs**

F1×F1	F2×F1	F3×F1	F4×F1	F5×F1
F1×F2 16	F2×F2	F3×F2	F4×F2	F5×F2
F1×F3 12	F2×F3 12	F3×F3	F4×F3	F5×F3
F1×F4 8	F2×F4 8	F3×F4 6	F4×F4	F5×F4
F1×F5 8	F2×F5 8	F3×F5 6	F4×F5 4	F5×F5

parameter pair F2,F3 has 12 possible values

parameter pair F4,F5 has 4 possible values

Total of 88 value-pairs

Getting the Problem Under Control



192 possible configurations

Pairwise: thorough testing with only 16 configurations

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16
F1	0	1	2	3	0	1	2	3	0	1	2	3	0	1	2	3
F2	0	0	0	0	1	1	1	1	2	2	2	2	3	3	3	3
F3	0	1	2	1	2	0	1	0	1	2	0	2	0	1	2	1
F4	0	1	1	0	0	1	0	1	1	0	0	0	0	1	0	1
F5	0	1	0	0	1	0	1	1	0	1	1	0	0	1	0	1

- Probably the best we can do with that number of tests

- Widely applicable:

- configuration
- parameterization
- stimulus scenarios

Larger example

- 20 parameters, each with 10 values
- 10^{20} possible configurations
- Pairwise covered by **230** tests
- Generator runtime ~20 seconds

Using our N-wise Implementation



- Pure SystemVerilog
 - fits easily into typical verification flow
 - compatible with UVM and other methodologies
 - uses SV constraint language for flexibility
- Minimal restriction on your coding style
- Small overhead if you add the code but don't use it
- Development continues, but the current implementation is already useful
 - freely available from www.verilab.com

Code for Register Example

- Minimal coding overhead in user's configuration object

```
`include "nwise.svh"

typedef enum {P_NONE, P_ODD, P_EVEN} parity_e;

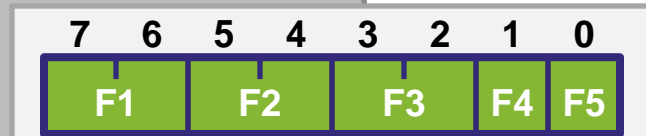
class Config extends
    Nwise_base#(uvm_sequence_item);

...
`NWISE_BEGIN(Config)
`NWISE_VAR_INT(    int,      F1, {[0:3]} )
`NWISE_VAR_INT(    bit[1:0], F2 )
`NWISE_VAR_ENUM(    parity_e, F3 )
`NWISE_VAR_INT(    bit,      F4 )
`NWISE_VAR_INT(    bit,      F5 )

    string name;
    function new(...); ...
endclass
```

Mixin supports
UVM base classes
if required

Value-set required
for wide types



```
rand int F1;
constraint c_NWISE_F1 {
    F1 inside {[0:3]};
    F1 == __nwise_value_proxy[...];
}
```

Macro-generated
code (simplified)

Other user code OK

Using the N-wise Enabled Class

- Call methods of class's generator object to get patterns

```
class Config extends Nwise_base#
```

Generator object

Generation order:
2 for pairwise

```
...
\ NWISE_BEGIN(Config)
\ N
\ N
```

```
Config cfg = new(...);
int num_patterns = cfg.nwise.generate_patterns(2);
for (int p = 0; p < num_patterns; p++) begin
    cfg.nwise.render_pattern(p);
    $display("cfg %2d = %b,%b,%s,%b,%b",
            p, cfg.F1, cfg.F2, cfg.F3.name, cfg.F4, cfg.F5);
end
```

```
cfg 0 = 00,00,P_NONE,0,0
cfg 1 = 01,00,P_ODD,1,1
cfg 2 = 10,00,P_EVEN,1,0
```

- render_pattern(p):**
Change this object's contents to match **pattern[p]**
- render_pattern_new(p):**
Make a **new** object with contents matching **pattern[p]**

Under the Hood

```
class C extends Nwise_base; class Nwise_base ...
```

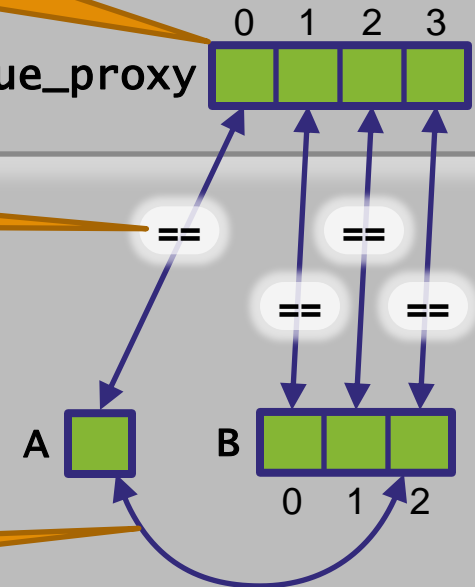
Generation algorithms work on this array –
no direct interaction with user variables

__nwise_value_proxy

Macro-generated
equality constraints

```
`NWISE_BEGIN(C)
`NWISE_VAR_INT( bit[1:0], A )
`NWISE_VAR_INT_ARRAY( bit, B, 3 )
constraint user_c {
    B[2] -> (A != 0)
}
...
```

All user constraints
honored by generation



Performance

- Pairwise efficiency (test compression)
 - currently within ~15%-30% of best available tools, ~10% of PICT

Problem space		Number of patterns for pairwise coverage		
<i>cardinality</i>	<i>params</i>	<i>our tool</i>	<i>PICT</i>	<i>best available</i>
2	100	16	15	10
3	12	20	18	15
4	10	22	21	18

Runtime on VCS H-2013.06
(64-bit Linux, modest x86 server)

- insignificant on small problems
- for N-wise, scales as $\text{cardinality}^{2N} \times \text{params}^4$
- ~7 seconds for 2^{100} example

data from ref [2]
in our paper

Additional Features, Future Work

- API improvements
 - specify required patterns to include in the set
e.g. key early customer configuration
 - higher-order interactions for selected parameters
e.g. pairwise, with 3-wise for some set of critical parameters
 - incremental pattern generation for fast startup
- Ongoing work on performance, capacity
- Support variable-size arrays

Details will be influenced by real-world experience

Application Suggestions

- Alternative to randomization for UVM configuration objects
 - choice of TB options, selection of tests, register settings...
- Provide successive values for a DUT control register
 - especially useful when each register setup needs extensive testing
- Choose build parameters for configurable IP
 - always requires a 2-pass approach
(module parameters must be static)
- Configuration of embedded software to run on DUT

Time to Play!

- Get the code and user notes
 - Apache open-source license, just like the UVM code

www.verilab.com/resources

- Check out other available implementations
 - see the references in our paper
 - compare
 - usability
 - convenience
 - performance
 - compatibility with your existing flow

Thank You

